



Docket No. AMDP458US

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re **PATENT** application of:

Applicant: Ramkumar Subramanian et al.
Application No.: 09/634,302
For: SYSTEM AND METHOD FOR DEFECT IDENTIFICATION AND
LOCATION USING AN OPTICAL INDICIA DEVICE
Filing Date: August 8, 2000
Examiner: Richard A. Rosenberger
Art Unit: 2877

REPLY TO OFFICE ACTION DATED NOVEMBER 1, 2002

Box Non-Fee Amendment
Assistant Commissioner for Patents
Washington, D.C. 20231

Dear Sir:

Favorable reconsideration of the above-identified application is respectfully requested in view of the following amendments and remarks.

AMENDMENTS

IN THE CLAIMS:

Please cancel claims 1-7, 12, 14-16, and 23 without prejudice or disclaimer, and amend claims 8 and 13 as provided below. An appendix illustrating the amended claims in "marked up" form is provided at the end of this response for the Examiner's ease of reference.

- 9) 8. (Amended) An optical defect inspection system for identifying and locating defects in a workpiece, comprising:
- an optical measurement device adapted to view the workpiece along an optical path; and
 - an optical indicia device located in the optical path, adapted to provide location information with respect to a defect in the workpiece;

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